Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/622,733	LU ET AL.	
Examiner	Art Unit	
Nhan T. Tran	2622	

SEARCHED					
Subclass	Date	Examiner			
297	10/6/2006	NT			
		-			

		297 10/6/2006			

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
	<u> </u>					

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	10/6/2006	NT
348/294-299 (text search - see search history printout)	10/9/2006	NT
348/229.1, 294-324, 362 (text search - see search history printout)	10/10/2006	NT
Inventorship search - see search history printout	10/13/2006	NT